

**Notice of References Cited**

Application/Control No.

10/580,115

Applicant(s)/Patent Under  
Reexamination  
KIM, YONG HEE

Examiner

JASON Y. KO

Art Unit

1792

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0140517	07-2003	Schmid, Bertram	34/78
*	B	US-5,277,210	01-1994	Kim, Shin-Yong	134/95.2
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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